Related records can be viewed between 8:30 a.m. and 5 p.m. in Suite 4100W, U.S. Department of Commerce, Franklin Court Building, 1099 14th Street, NW., Washington, DC.

Docket Number: 05-002.

Applicant: Cornell University, Ithaca, NY 14853.

Instrument: KB Mirror System.

Manufacturer: Khozu Precision Co.,
Ltd., Japan.

Intended Use: See notice at 70 FR February 7, 2005.

Comments: None received.

Decision: Approved. No apparatus of equivalent scientific value to the foreign apparatus, for such purposes as it is intended to be used, is being manufactured in the United States.

Reason: This is a compatible accessory for an existing instrument purchased for the use of the applicant. The accessory is pertinent to the intended uses and we know of no domestic accessory which can be readily adapted for use with the existing instrument.

Gerald A. Zerdy,

 $\label{lem:program} \textit{Program Manager, Statutory Import Programs Staff.}$

[FR Doc. E5–1173 Filed 3–16–05; 8:45 am] BILLING CODE 3510–DS–P

DEPARTMENT OF COMMERCE

International Trade Administration

Applications for Duty-Free Entry of Scientific Instruments

Pursuant to Section 6(c) of the Educational, Scientific and Cultural Materials Importation Act of 1966 (Pub. L. 89–651; 80 Stat. 897; 15 CFR part 301), we invite comments on the question of whether instruments of equivalent scientific value, for the purposes for which the instruments shown below are intended to be used, are being manufactured in the United States.

Comments must comply with 15 CFR 301.5(a)(3) and (4) of the regulations and be filed within 20 days with the Statutory Import Programs Staff, U.S. Department of Commerce, Washington, DC 20230. Applications may be examined between 8:30 a.m. and 5 p.m. in Suite 4100W, U.S. Department of Commerce, Franklin Court Building, 1099 14th Street, NW., Washington, DC.

Docket Number: 00-011.

Applicant: Johns Hopkins University, School of Medicine, Microscope Facility, 725 N. Wolfe Street, Physiology Building, Room G–4, Baltimore, MD 21205. *Instrument:* Electron microscope, Model H–7600–I.

Manufacturer: Hitachi High-Technologies Corporation, Japan.

Intended Use: The instrument is intended to be used to investigate:

- (1) The mechanical properties of intermediate filaments composed of keratin;
- (2) The structure and replication mechanism of kinoplast DNA;
- (3) The basis of bacterial gliding motility by means of slime expulsion in certain prokaryotic cells;
- (4) The mechanism of membrane protein delivery to the plasma membrane in mammalian cells;
- (5) Identification of novel genes that play critical roles in the development of the retina.

Application accepted by Commissioner of Customs: February 25, 2005.

Docket Number: 05-012.

Applicant: University of Chicago, 933 East 56th Street, Chicago, IL 60637.

Instrument: Pattern Selection Trigger.

Manufacturer: Hytec Electronics, Ltd.,
United Kingdom.

Intended Use: The instrument is intended to be used, in conjunction with a digital computer system, for a telescope to study high-energy gammarays of astronomical origin.

Application accepted by Commissioner of Customs: February 28, 2005.

Docket Number: 05-013.

Applicant: National Institute of Standards and Technology.

Instrument: Focused Ion Beam Field Emission Scanning Electron Microscope, Model Nova 600 NanoLab.

Manufacturer: FEI Company, The Netherlands.

Intended Use: The instrument is intended to allow complex, chemically heterogeneous materials to be both synthesized using materials deposition from gas injection systems, and to be sectioned and ion milled using a Gallium ion beam for removal of material for study of the gross morphology, crystal structure and microstructure, chemical composition, electronic structure, and transport properties of materials to be measured on nanometer length scales. The phenomena of electron scattering, x-ray generation, beam transport, absorption and internal fluoresence will be studied to perform quantitative analyses of nanoscale materials for numerous ongoing research projects.

Application accepted by Commissioner of Customs: March 2, 2005.

Gerald A. Zerdy,

Program Manager, Statutory Import Programs Staff.

[FR Doc. E5–1172 Filed 3–16–05; 8:45 am]
BILLING CODE 3510–DS–P

DEPARTMENT OF COMMERCE

Submission for OMB Review; Comment Request

The Department of Commerce has submitted to the Office of Management and Budget (OMB) for clearance the following proposal for collection of information under the provisions of the Paperwork Reduction Act (44 U.S.C. Chapter 35).

Agency: National Oceanic and Atmospheric Administration (NOAA).

Title: Southwest Region Permit Family of Forms—Pacific. Form Number(s): None.

Form Number(s): None.

OMB Approval Number: 0648–0490.

Type of Request: Regular submission.

Burden Hours: 85. Number of Respondents: 200. Average Hours per Response: 23 minutes.

Needs and Uses: The permits are required for persons to participate in federally-managed fisheries in the western Pacific region and off the U.S. West Coast. The Western Pacific Fishery Management Council has recommended the National Marine Fisheries Service's (NMFS) approval and implementation of Amendment 11 to the Fishery Management Plan for the Pelagic Fisheries of the Western Pacific Region. Amendment 11 would establish a limited access permit program for the American Samoa-based pelagic longline fishery which necessitates a revised collection of information. The program requires information from potential initial participants and subsequent new entrants (via permit transfers) in the fishery. NMFS will use the information to determine who is eligible for issuance of American Samoa longline limited access permits. The fishermen will be required to use appropriate permit application forms/supplementary information sheets provided by NMFS.

Affected Public: Business or other forprofit organizations; Individuals or households.

Frequency: Variable.

Respondent's Obligation: Mandatory. OMB Desk Officer: David Rostker, (202) 395–3897.

Copies of the above information collection proposal can be obtained by calling or writing Diana Hynek,